

CMOS Microprocessor Compatible Double-Buffered 12-Bit Digital-to-Analog Converter

### **FEATURES**

- Superior Ruggedized 1230 Series: 2 KV ESD
- Four Quadrant Multiplication
- Stable, More Accurate Segmented DAC Approach
  - 0.2 ppm/°C Linearity Tempco
  - 2 ppm/°C Max Gain Error Tempco
  - Lowest Sensitivity to Amplifier Offset
  - Lowest Output Capacitance (C<sub>OUT</sub> = 80pF)
  - Lower Glitch Energy
- Monotonic over Temperature Range

- Lower Data Bus Feedthrough @ CS = 1
- V<sub>DD</sub> from +11 V to +16 V
- Latch-Up Free CMOS Technology
- 12-Bit Bus Version: MP1208/1209/1210
- 16-Bit Upgrade: MP7636A

#### **GENERAL DESCRIPTION**

The MP1230A series are superior pin for pin replacements for the 1230 series. The MP1230A series is manufactured using advanced thin film resistors on a double metal CMOS process which promotes significant improvements in reliability, latch-up free performance and ESD protection.

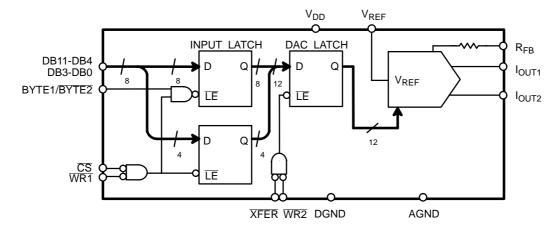
The MP1230A series incorporates a unique decoding technique yielding lower glitch, higher speed and excellent accuracy over temperature and time. 12-bit linearity is achieved without trimming. Outstanding features include:

 Stability: integral and differential linearity tempcos are rated at 0.2 ppm/°C typical. Monotonicity is guaranteed over all temperature ranges. Scale factor tempco is a low 2 ppm/°C maximum.

- Low Output Capacitance: Due to smaller MOSFET switch geometries allowed by decoding, the output capacitance at I<sub>OUT1</sub> and I<sub>OUT2</sub> is a low 80pF / 40pF and 25pF / 65 pF. This less than half the competitive DAC 1230 series. Lower capacitance allows the MP1230A series to achieve settling times faster than 1 μs for a 10 V step.
- Low Sensitivity to Output Amplifier Offset: The linearity error caused by amplifier offset is reduced by a factor of 2 in the MP1230A series over conventional R-2R DACs.

The MP1230A series uses a circuit which reduces transients in the supplies caused by DATA bus transitions at  $\overline{CS} = 1$ .

### SIMPLIFIED BLOCK DIAGRAM



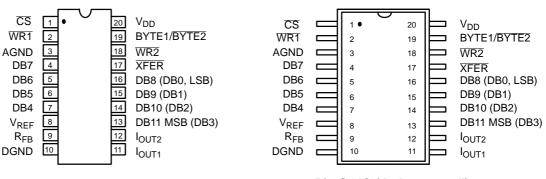




### ORDERING INFORMATION

Package Type	Temperature Range	Part No.	INL (LSB)	DNL (LSB)	Gain Error (% FSR)
Plastic Dip	–40 to +85°C	MP1230ABN	<u>+</u> 1/2	<u>+</u> 3/4	<u>+</u> 0.4
Plastic Dip	–40 to +85°C	MP1231ABN	<u>+</u> 1	<u>+</u> 1	<u>+</u> 0.4
Plastic Dip	–40 to +85°C	MP1232ABN	<u>+</u> 2	<u>+</u> 2	<u>+</u> 0.4
SOIC	–40 to +85°C	MP1230ABS	<u>+</u> 1/2	<u>+</u> 3/4	<u>+</u> 0.4
SOIC	–40 to +85°C	MP1231ABS	<u>+</u> 1	<u>+</u> 1	<u>+</u> 0.4
SOIC	–40 to +85°C	MP1232ABS	<u>+</u> 2	<u>+</u> 2	<u>+</u> 0.4

### PIN CONFIGURATIONS See Packaging Section for Package Dimensions



20 Pin PDIP (0.300") N20

20 Pin SOIC (Jedec, 0.300") S20

### **PIN OUT DEFINITIONS**

PIN NO.	NAME	DESCRIPTION	PIN NO.	NAME	DESCRIPTION
1 2	CS WR1	Chip Select (Active Low) Write 1 (Active Low)	12 13	I <sub>OUT2</sub> DB11 (DB3)	Current Output 2 Data Input Bit 11 (MSB)
3 4	AGND DB7	Analog Ground  Data Input Bit 7	14	DB10 (DB2)	Data Input Bit 17 (MOB)  Data Input Bit 3  Data Input Bit 10  Data Input Bit 2
5 6	DB6 DB5	Data Input Bit 6 Data Input Bit 5	15	DB9 (DB1)	Data Input Bit 9 Data Input Bit 1
7	DB4	Data Input Bit 4	16	DB8 (DB0)	Data Input Bit 8 Data Input Bit 0 (LSB)
8	V <sub>REF</sub>	Reference Input Voltage	17	XFER	Transfer Control Signal (Active Low)
9	$R_{FB}$	Feedback Resistor	18	WR2	Write 2 (Active Low)
10	DGND	Digital Ground	19	BYTE1/	Byte Sequence Control
11	I <sub>OUT1</sub>	Current Output 1		BYTE2	
			20	$V_{DD}$	Positive Power Supply

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# ELECTRICAL CHARACTERISTICS (VDD = + 15 V, VREF = +10 V unless otherwise noted)

Parameter	Symbol	Min	25°C Typ	Max	Tmin to	Tmax Max	Units	Test Conditions/Comments
STATIC PERFORMANCE <sup>1</sup>	Cymbol		176	- Wida		mux	Onito	FSR = Full Scale Range
		40			40		D''-	1 Six = 1 dii Sodie Rango
Resolution (All Grades)	N	12			12		Bits	
Integral Non-Linearity (Relative Accuracy)	INL						LSB	Best Fit Straight Line Spec. (Max INL – Min INL) / 2
MP1230ABN/ATD/ABS MP1231ABN/ATD/ABS				<u>+</u> 1/2 <u>+</u> 1		<u>+</u> 1/2 <u>+</u> 1		
MP1232ABN/ATD/ABS				<u>+</u> 2		<u>+</u> 2		
Differential Non-Linearity	DNL						LSB	
MP1230ABN/ATD/ABS MP1231ABN/ATD/ABS				<u>+</u> 3/4 <u>+</u> 1		<u>+</u> 3/4 <u>+</u> 1		
MP1232ABN/ATD/ABS				<u>+</u> 2		<u>+</u> 2		
Gain Error	GE			<u>+</u> 0.4		<u>+</u> 0.4	% FSR	Using Internal R <sub>FB</sub>
Gain Temperature Coefficient <sup>2</sup>	$TC_GE$		0.5			<u>+</u> 2	ppm/°C	$\Delta$ Gain/ $\Delta$ Temperature
Power Supply Rejection Ratio	PSRR		5	<u>+</u> 20		<u>+</u> 20	ppm/%	$ \Delta Gain/\Delta V_{DD}  \Delta V_{DD} = \pm 0.25V$
Output Leakage Current	l <sub>out</sub>		1	<u>+</u> 10		<u>+</u> 200	nA	
DYNAMIC PERFORMANCE <sup>2</sup>								$R_L$ =100 $\Omega$ , $C_L$ =13pF
Current Settling Time	ts		1.0				μsec	Full Scale Change to 1/2 LSB
AC Feedthrough at I <sub>OUT1</sub>	F <sub>T</sub>		1.0				mV p-p	V <sub>REF</sub> =100kHz, 20Vp-p, sinewave
REFERENCE INPUT								
Input Resistance	R <sub>IN</sub>	5	10	20	5	20	kΩ	
DIGITAL INPUTS								
Logical "1" Voltage	$V_{IH}$	3.0	2.4		3.0		٧	
Logical "0" Voltage Input Leakage Current	V <sub>IL</sub> I <sub>LKG</sub>			0.8 <u>+</u> 1		0.8 <u>+</u> 1	V μA	V <sub>IN</sub> = 0, 5 V
Input Capacitance <sup>2</sup>			10				pF	
ANALOG OUTPUTS <sup>2</sup>								
Output Capacitance							_	
	C <sub>OUT1</sub> C <sub>OUT1</sub>		80 40	100 60		100 60	pF pF	DAC Inputs all 1's DAC Inputs all 0's
	C <sub>OUT2</sub> C <sub>OUT2</sub>		65 25	85 45		85 45	pF pF	DAC Inputs all 1's DAC Inputs all 0's
POWER SUPPLY								
Functional Voltage Range <sup>4</sup>	$V_{DD}$	+4.5		+16	+4.5	+16	V	
Supply Current	I <sub>DD</sub>		1.2	2.0		2.0	mA	All digital inputs = 0 V or all = 5 V





### **ELECTRICAL CHARACTERISTICS (CONT'D)**

Parameter	Symbol	Min	25°C Typ	Max	Tmin to Min	Tmax Max	Units	Test Conditions/Comments
SWITCHING CHARACTERISTICS <sup>2, 3</sup>								
Chip Select to Write Set-Up Time Chip Select to Write Hold Time Data Valid to Write Set-Up Time Data Valid to Write Hold Time Write Pulse Width,	t <sub>CS</sub> t <sub>CH</sub> t <sub>DS</sub> t <sub>DH</sub> t <sub>WR</sub>	200 10 100 90 100	100 0 50 70 50				ns ns ns ns	

### NOTES:

- Full Scale Range (FSR) is 10V.
- Guaranteed but not production tested.
- 3 See timing diagram.
- <sup>4</sup> Specified values guarantee functionality. Refer to other parameters for accuracy.

Specifications are subject to change without notice

### ABSOLUTE MAXIMUM RATINGS (TA = +25°C unless otherwise noted)<sup>1, 2</sup>

V <sub>DD</sub> to GND+17 V	Storage Temperature65°C to +150°C
Digital Input Voltage to GND GND –0.5 to V <sub>DD</sub> +0.5 V	
I <sub>OUT1</sub> , I <sub>OUT2</sub> to GND	Lead Temperature (Soldering, 10 seconds) +300°C
V <sub>REF</sub> to GND <u>+</u> 25 V	Package Power Dissipation Rating to 75°C
V <sub>RFB</sub> to GND <u>+</u> 25 V	
AGND to DGND	CDIP, PDIP, SOIC 900mW
(Functionality Guaranteed ±0.5 V)	Derates above 75°C

### NOTES:

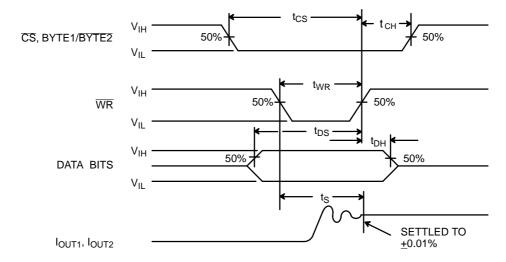
Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation at or above this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Any input pin which can see a value outside the absolute maximum ratings should be protected by Schottky diode clamps (HP5082-2835) from input pin to the supplies. *All inputs have protection diodes* which will protect the device from short transients outside the supplies of less than 100mA for less than 100µs.

3 GND refers to AGND and DGND.



### **TIMING DIAGRAM**



### **DEFINITION OF CONTROL SIGNALS:**

CS: Chip Select.(Active low)

It will enable WR1.

WR1: Write 1 (Active low)

The WR1 is used to load the digital data bits (DB) into

the input latch.

BYTE1/BYTE2: Byte sequence control.

The BYTE1/BYTE2 control pin is used to select both

MSB and LSB input latches.

WR2: Write 2 (Active low)

It will enable XFER.

XFER: Transfer control signal (Active low)

This signal in combination with  $\overline{WR2}$  causes the 16-bit

data which is available in the input latches to transfer

to the DAC register

DB0 to DB11: Digital Inputs.

DB0 is the least significant digital input (LSB) and

DB11 is the most significant digital input (MSB).

 $I_{OUT1}$ : DAC Current Output 1 Bus.

I<sub>OUT1</sub> is a maximum for a digital code of all 1's in the DAC register, and is zero for all 0's in the DAC register.

I<sub>OUT2</sub>: DAC Current Output 2 Bus.

 $I_{OUT2}$  is a complement of  $I_{OUT1}$ .

R<sub>FB</sub>: Feedback Resistor.

This internal feedback resistor should always be used (not an external resistor) since it matches the resistors

in the DAC and tracks these resistors over tempera-

ture.

V<sub>REF</sub>: Reference Voltage Input.

This input connects an external precision voltage source to the internal DAC. The V<sub>RFF</sub> can be selected

over the range of +25V to -25V or the analog signal for

a 4-quadrant multiplying mode application.

V<sub>DD</sub>: Power Supply Voltage.

This is the power supply pin for the part. The  $V_{DD}$  can

be from +5 V DC to +15 V DC, however optimum volt-

age is +12 to +15 V DC.

AGND: Analog Ground

Back gate of the DAC N-channel current steering

switches.

DGND: Digital Ground



### THEORY OF OPERATION

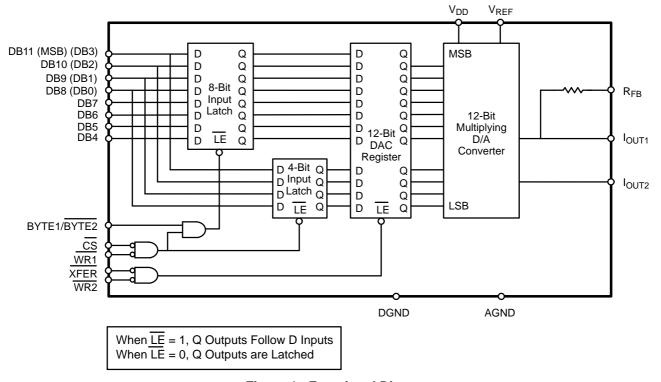


Figure 1. Functional Diagram

### **Digital Interface**

Figure 1. shows the internal control logic that controls the writing of the input latches. It is easy to understand how the MP1230A/31A/32A works by understanding each basic operation.

### **Writing to Input Latches**

The condition BYTE1/ $\overline{BYTE2}$ = high,  $\overline{CS} = \overline{WR1} = 0$  loads the data bus DB11-DB4 into both input latches.

A second cycle with BYTE1/ $\overline{BYTE2}$  = low (*Figure 2.*) loads the pins DB11-DB8 (DB3-DB0) into the 4-bit input latch.

Timing diagrams show the inputs  $\overline{\text{CS}}$  and DB11-DB0 to be stable during the entire writing cycle. In reality all the above signals can change (*Figure 2.*) as long as they meet the timing conditions specified in the Electrical Characteristic Table.

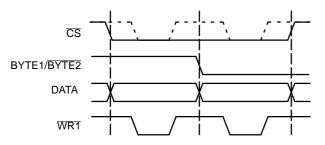


Figure 2. Write Cycles to Input Latches

### Transferring Data to the DAC Latches

Once one or all the input latches have been loaded, the condition  $\overline{XFER} = \overline{WR2} =$  low transfers the content of the input latches in the DAC latch. The outputs of the DAC latch change and the DAC current (I<sub>OUT</sub>) will reach a new stable value within the settling time  $t_S$  (*Figure 3*.).

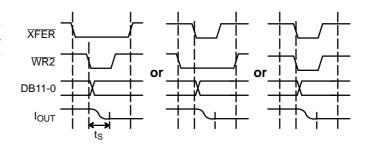
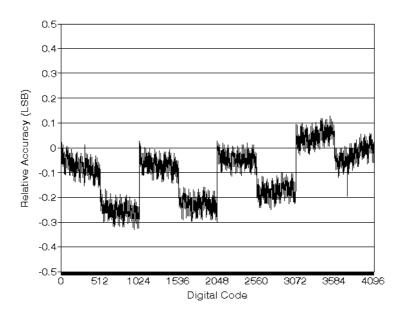


Figure 3. Transfer Cycles from Input Latches to DAC Latches

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### PERFORMANCE CHARACTERISTICS

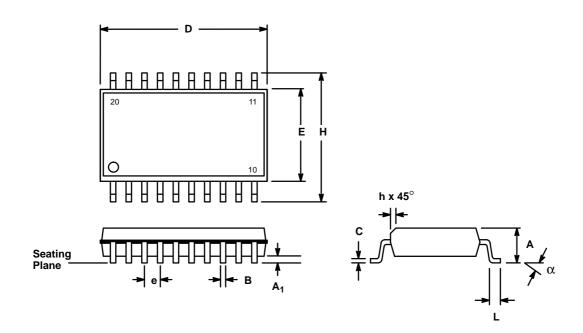


Graph 1. Relative Accuracy vs. Digital Code

APPLICATION NOTES
Refer to Section 8 for Applications Information



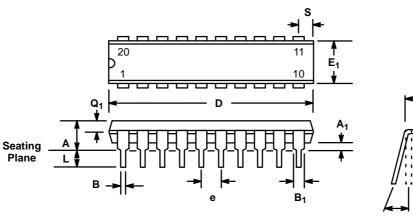
### 20 LEAD SMALL OUTLINE (300 MIL JEDEC SOIC) S20

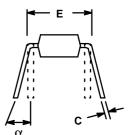


	INC	CHES	MILLIN	METERS
SYMBOL	MIN	MAX	MIN	MAX
Α	0.097	0.104	2.464	2.642
A <sub>1</sub>	0.0050	0.0115	0.127	0.292
В	0.014	0.019	0.356	0.483
С	0.0091	0.0125	0.231	0.318
D	0.500	0.510	12.70	12.95
Е	0.292	0.299	7.42	7.59
е	0.0	50 BSC	1.2	7 BSC
Н	0.400	0.410	10.16	10.41
h	0.010	0.016	0.254	0.406
L	0.016	0.035	0.406	0.889
α	0°	8°	0°	8°



### 20 LEAD PLASTIC DUAL-IN-LINE (300 MIL PDIP) N20





	INC	HES	MILLIMETERS		
SYMBOL	MIN	MAX	MIN	MAX	
Α	_	0.200		5.08	
A <sub>1</sub>	0.015	_	0.38	_	
В	0.014	0.023	0.356	0.584	
B <sub>1</sub> (1)	0.038	0.065	0.965	1.65	
С	0.008	0.015	0.203	0.381	
D	0.945	1.060	24.0	26.92	
E	0.295	0.325	7.49	8.26	
E <sub>1</sub>	0.220	0.310	5.59	7.87	
е	0.10	00 BSC	2.5	4 BSC	
L	0.115	0.150	2.92	3.81	
α	0°	15°	0°	15°	
Q <sub>1</sub>	0.055	0.070	1.40	1.78	
S	0.040	0.080	1.02	2.03	

Note: (1) The minimum limit for dimensions B1 may be 0.023" (0.58 mm) for all four corner leads only.



## **Notes**





# **Notes**





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